

Semiconductor Characterization System with Manual Probe Station

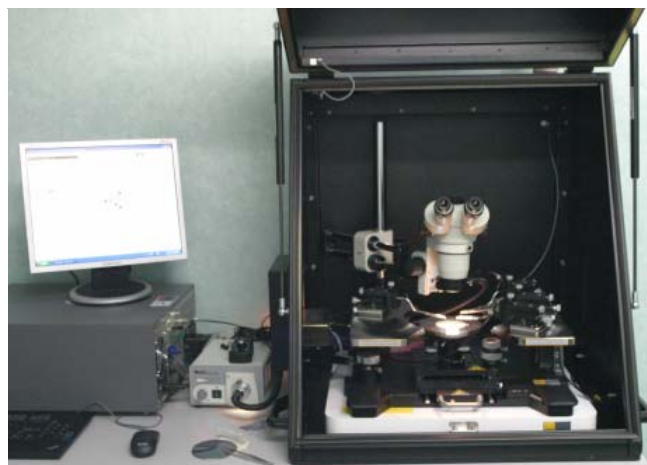
Manufacturer: Keithley; Suss MicroTec

Model: 4200 SCS/C/Keithley, EP6/ Suss MicroTec

Current upgrade status: 2x 4200-SMU and 2x4200-PA .

Fully programmable for on-wafer/structure sourcing and measuring of DC voltage and current simultaneously. 4200-SMU power: 2.2W (max.105mA, 210V). Per SMU preamplifier: 4200-PA with maximum measurement resolutions: 0.1fA, 5 μ V.

Shielded manual probe station with 4 triaxial cable manipulators. Measurements on wafers and substrates up to 150 mm (6"). Positioning resolution: 3 μ m.



Fiber Optic Spectrometer

Manufacturer: AVANTES

Model: AvaSpec-256-NIR2.2

Fiber Optic Spectrometer, 50 mm Avabench, 256 pixel InGaAs detector with 2 stage TEC, high speed USB2 interface, incl.AvaSoft-Basic, USB interface cable, NIRZ grating, 1100-2100 nm, OSF-1000 specify slit. Wavelength range: 1100-2100 nm; Resolution: 10.0-60 nm; Stray lighth: < 0.1%; Sensitivity: 80 counts (16-bit AD)/ μ W-per ms integration time; Semnal/Noise 1200:1; Integration time (min):0.52 ms.

Applications: Absorbance, transmittance/reflectance, luminescence.